

Simulations of the Secondary Electron Emission Detector for PALS Measurements

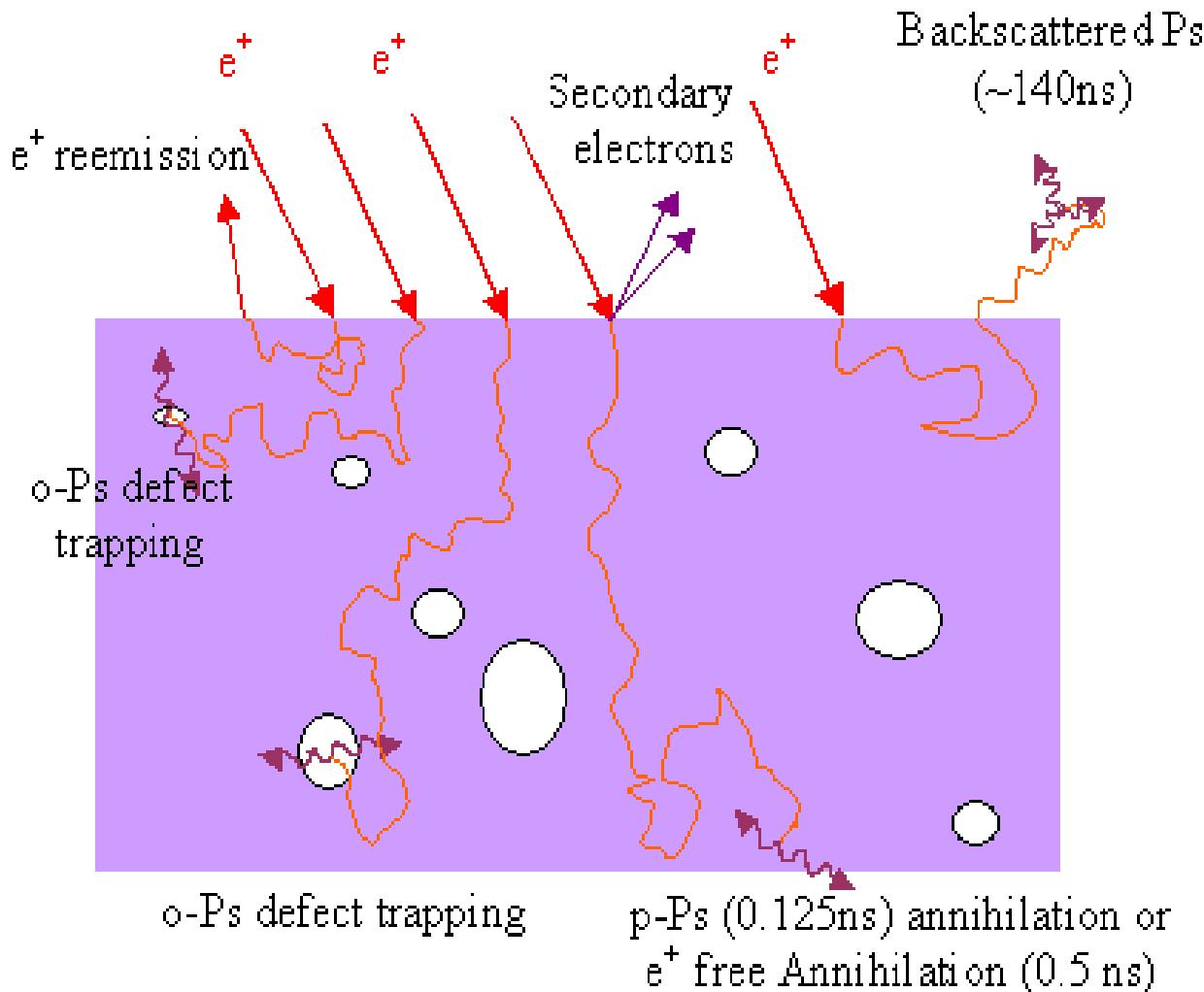
M.M. Kirsanov
INR RAS, Moscow

Workshop on Positron and Positronium
LAPP, Annecy
20-21 November 2007

Plan:

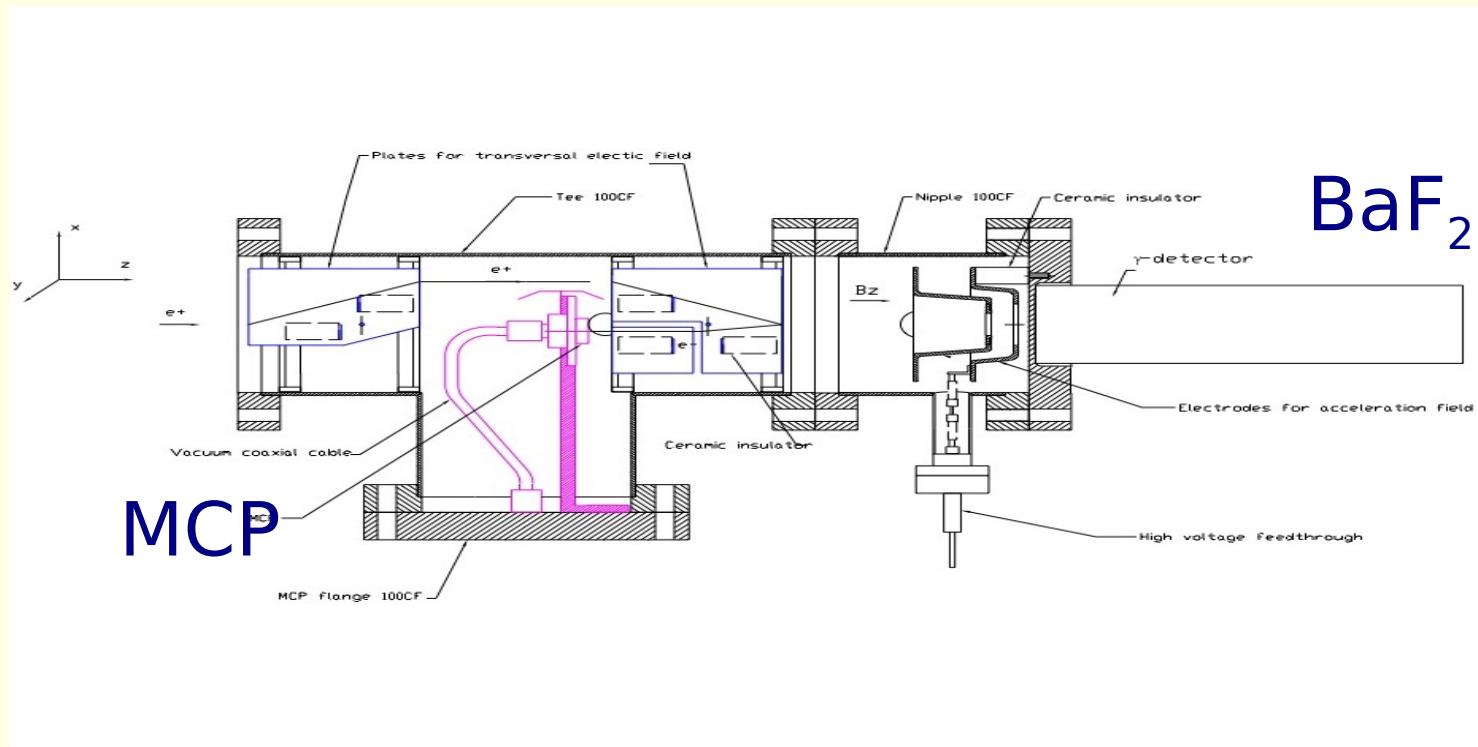
- PALS technique and its challenges
- High efficiency pulsed slow positron beam
- Positron lifetime spectrometer based on secondary electron emission
- Applications to thin films measurements
- Summary

Positron interactions with the surface



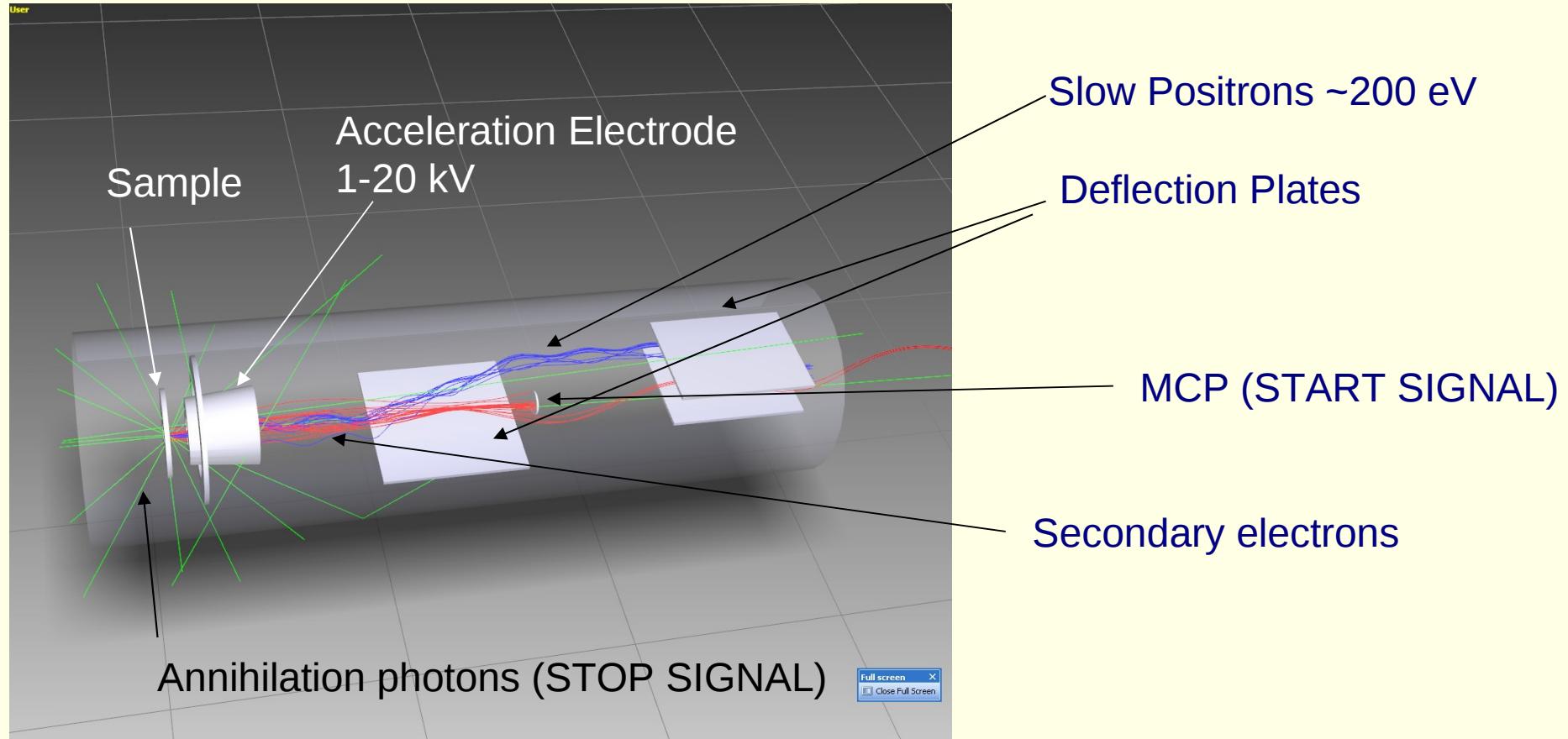
Secondary Electron Emission Detector

START: secondary electrons, STOP: annihilation gammas

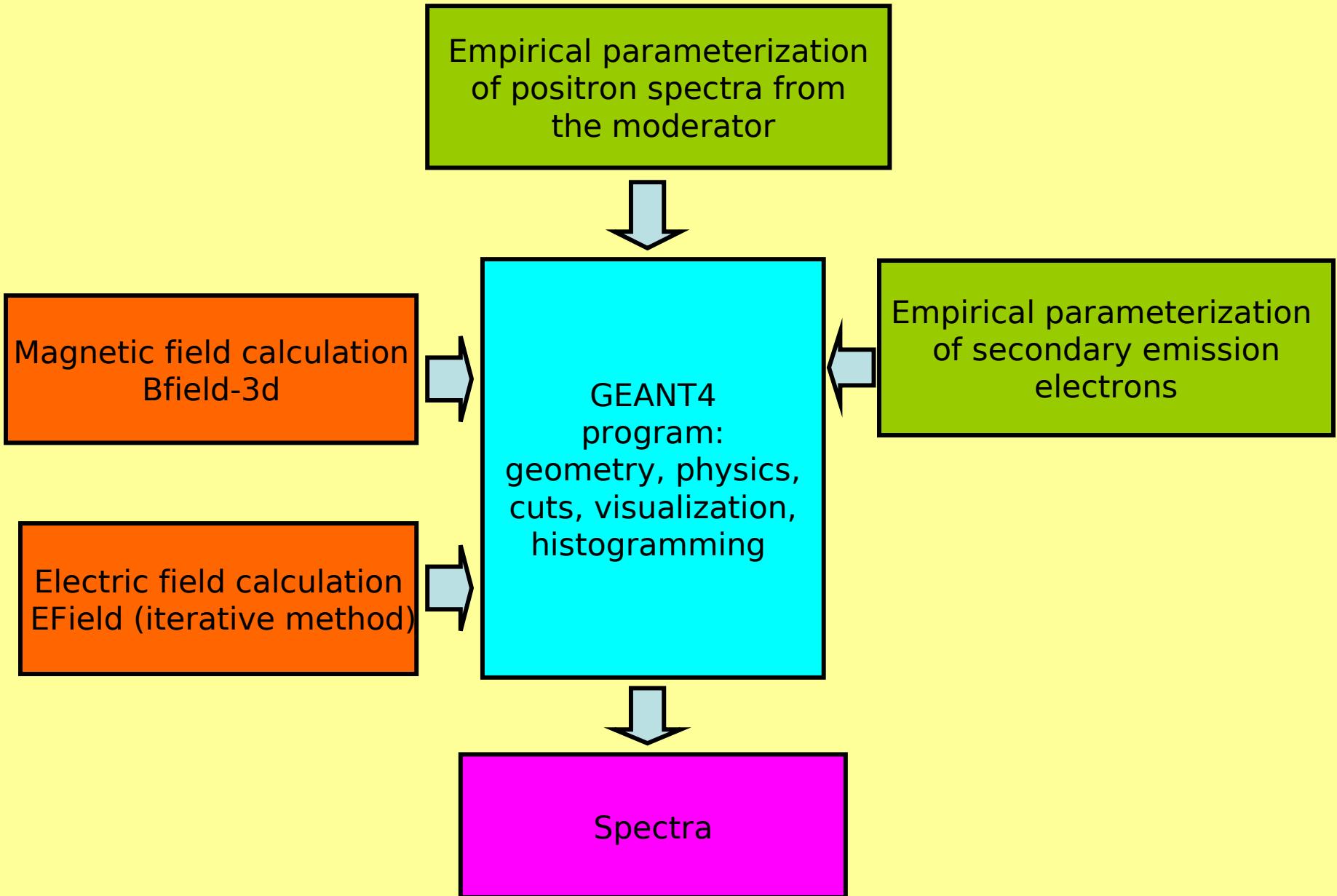


Secondary Electron Emission Detector

Simulation of SEED extraction optics:



Simulation scheme



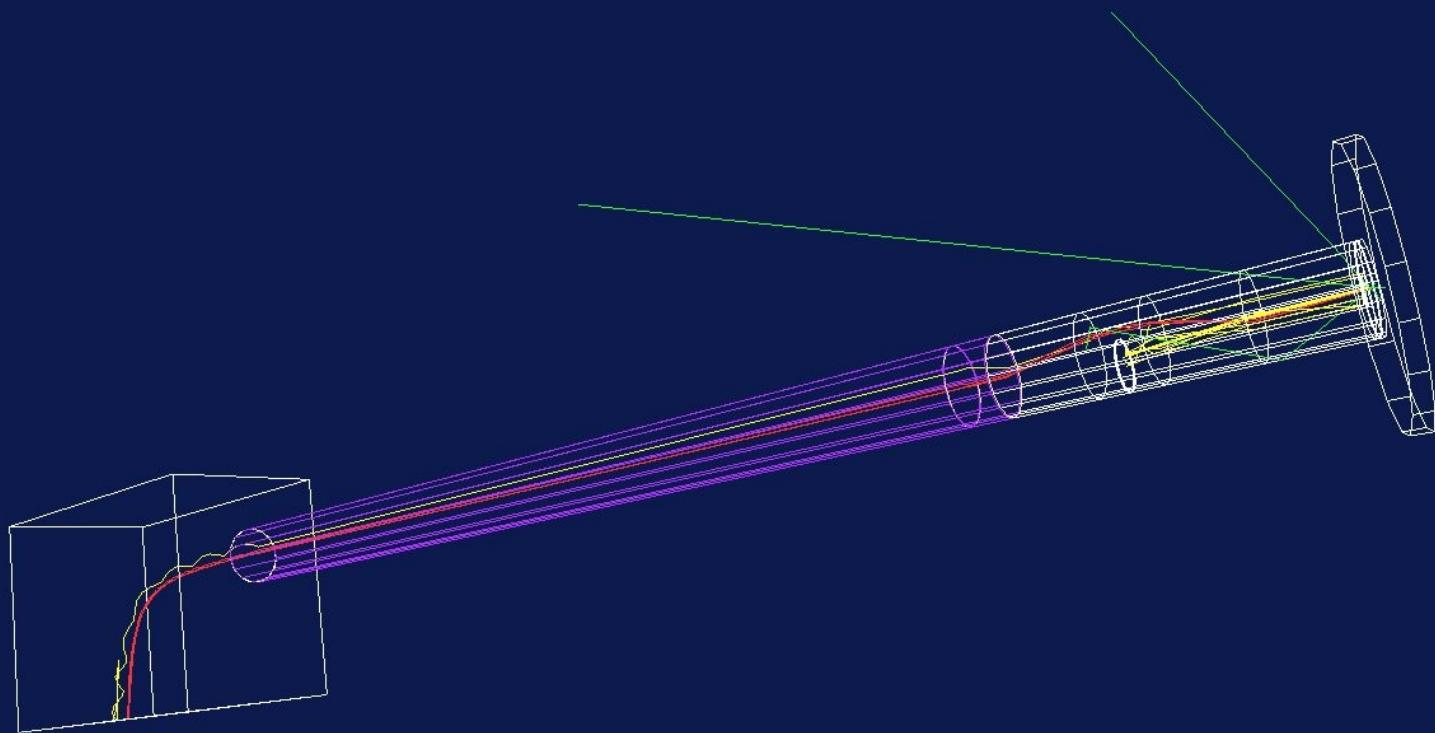
GEANT4

- Can simulate in the same program low, medium and high energy physics
- Is well supported on the modern computer platforms
- Many physicists are familiar with the GEANT4 toolkit
- We are in live contact with the authors of GEANT4, many of whom are based at CERN

Simulation geometry of the setup

File View SpecialFX Settings Camera Lights Windows

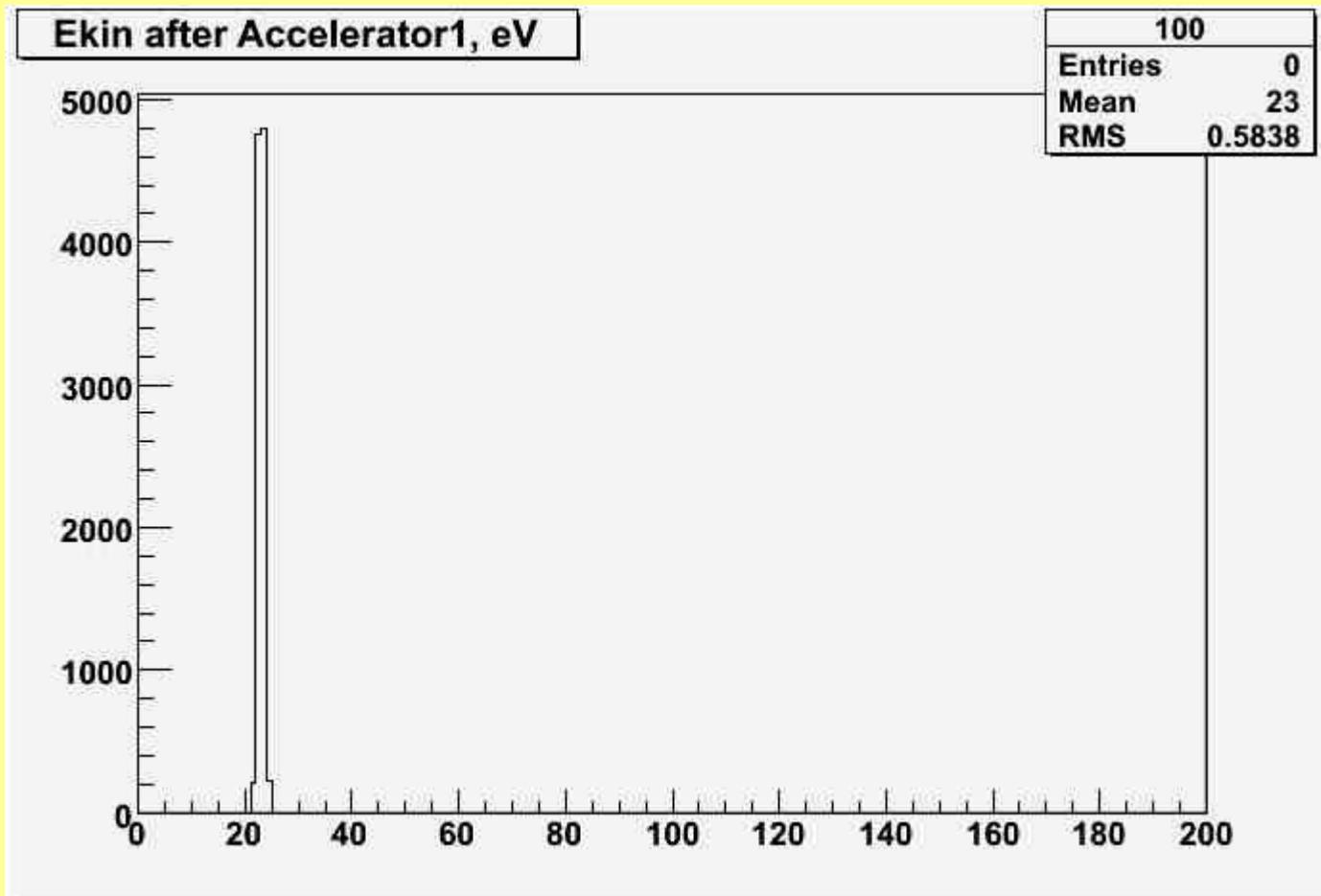
Help



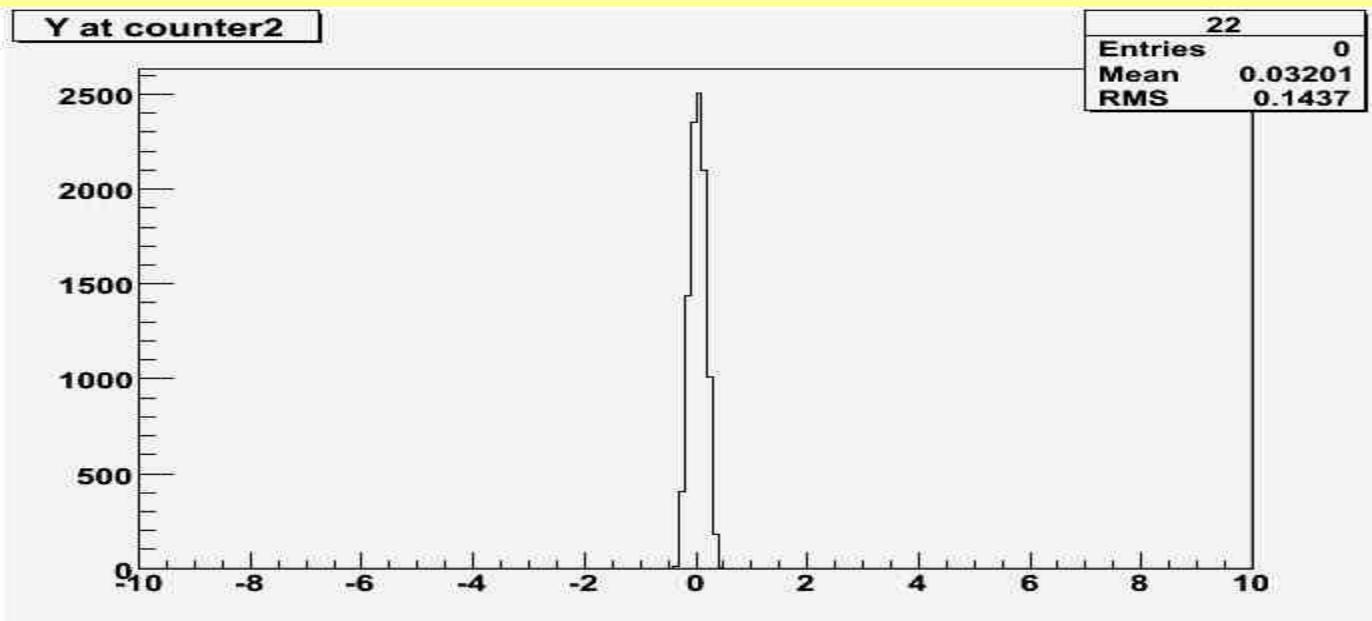
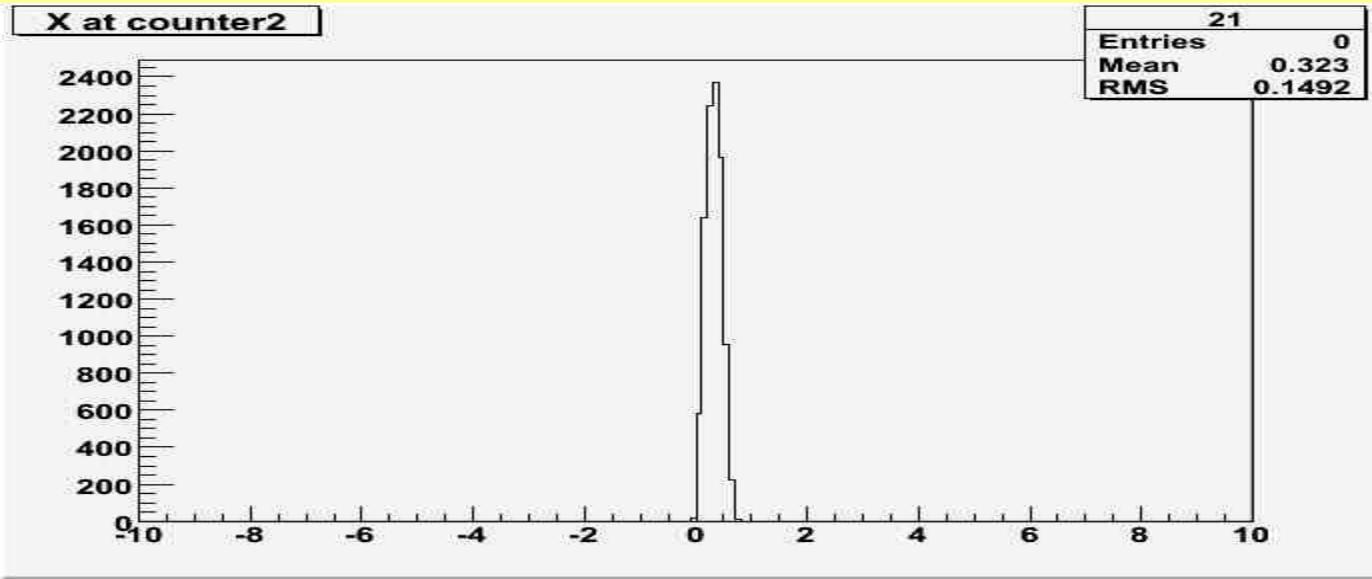
Cylinders : 194
Cubes : 182
Lines : 2388

Ready!

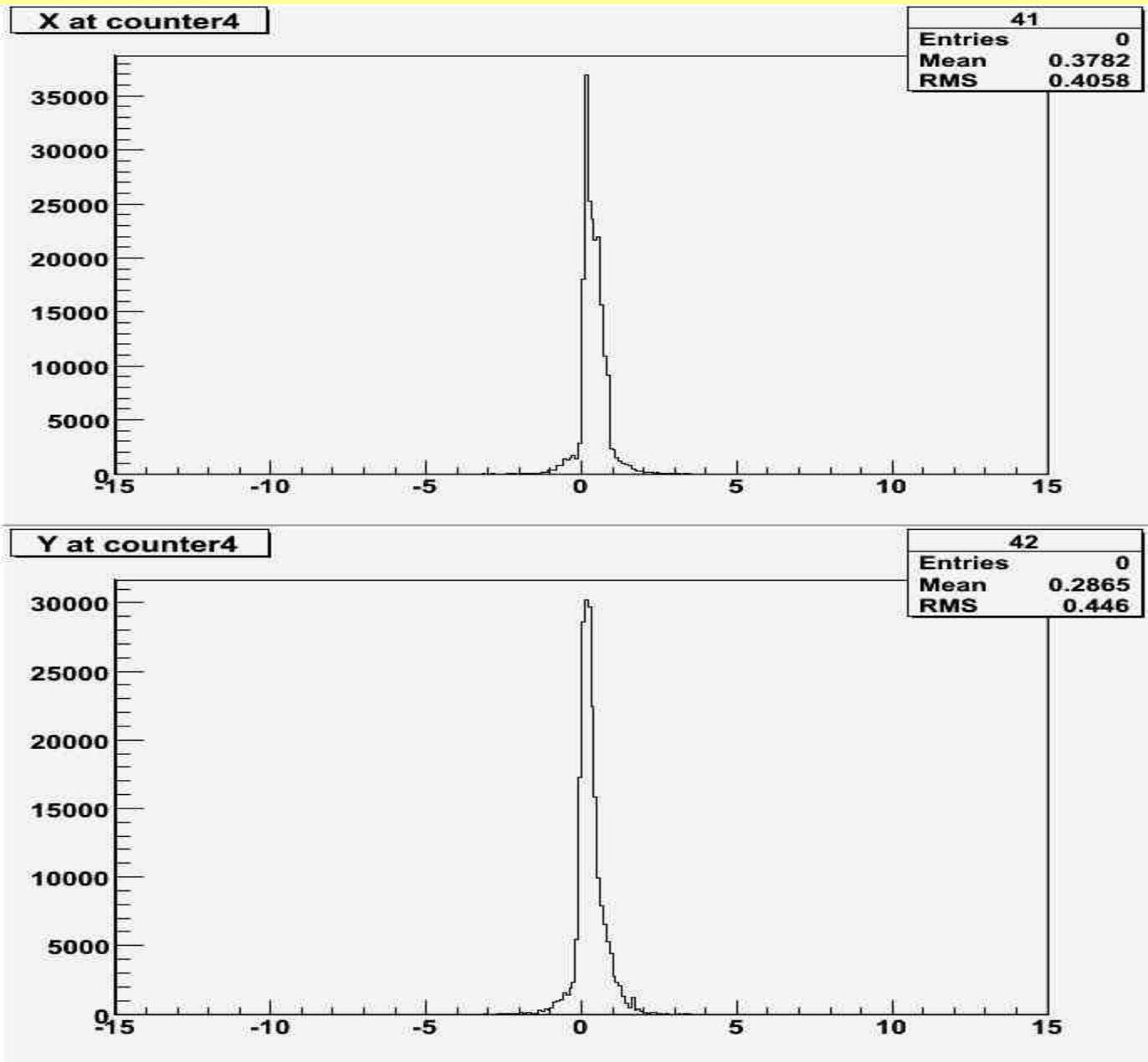
Positron energy after preliminary acceleration



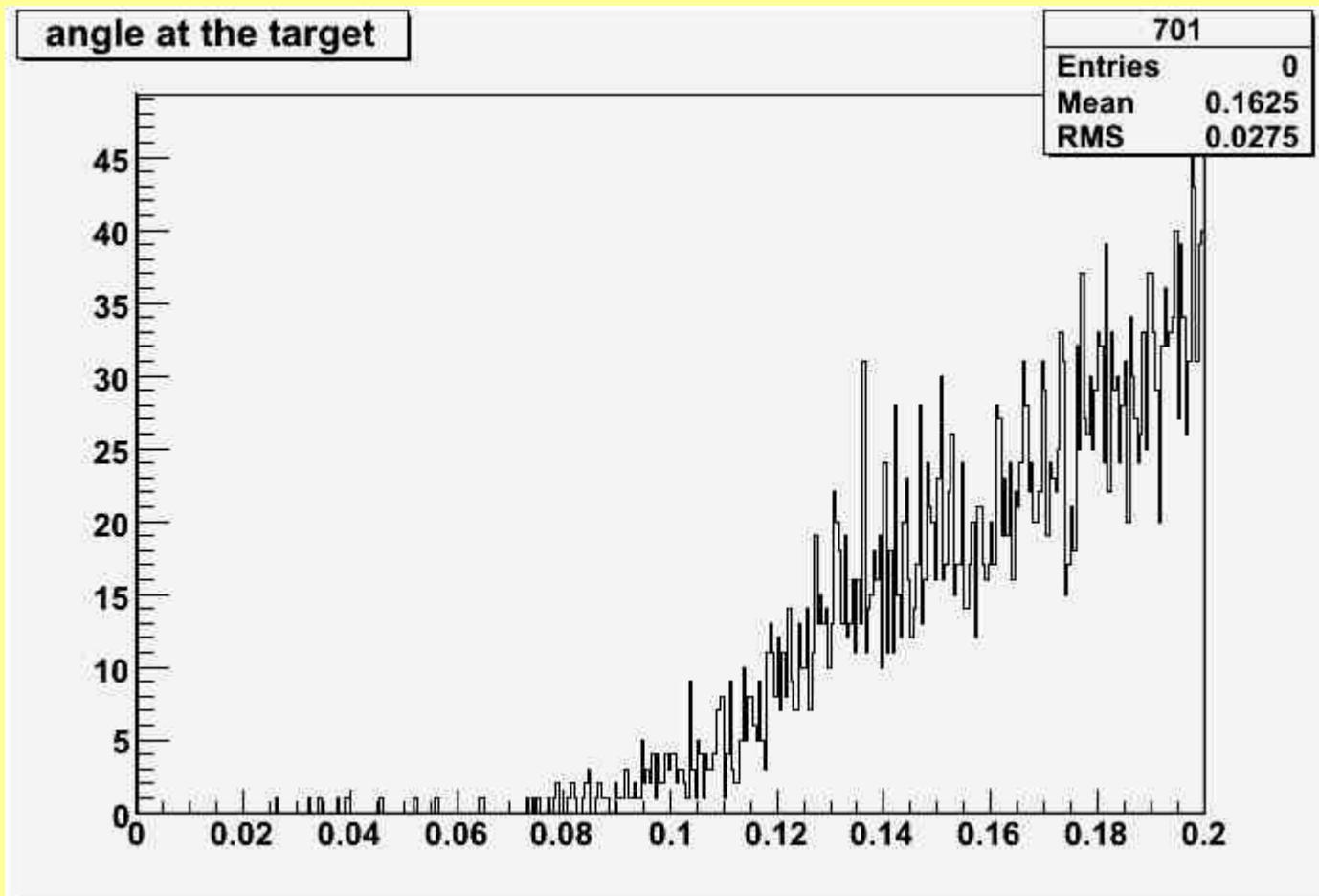
XY at the entrance



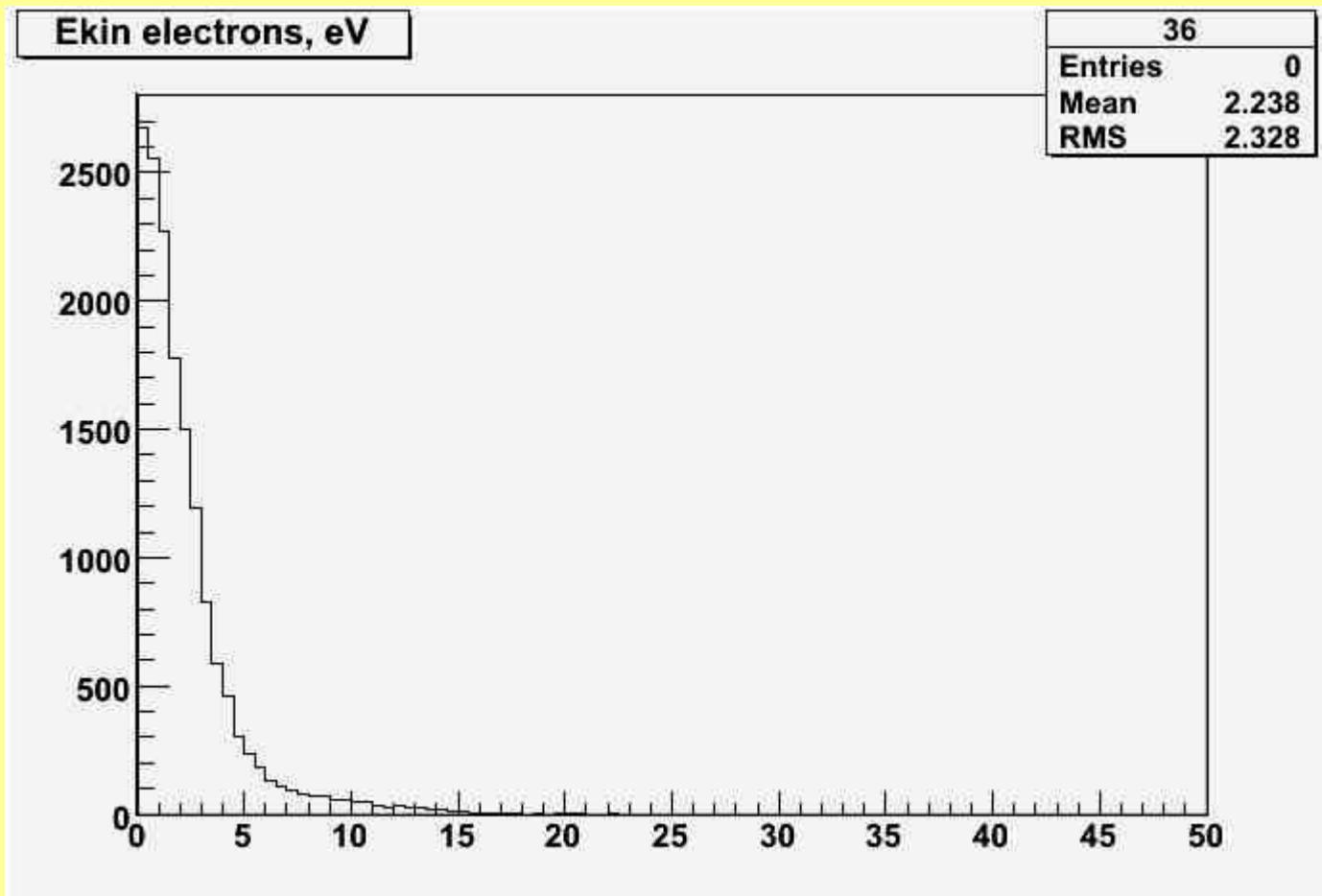
XY at the sample



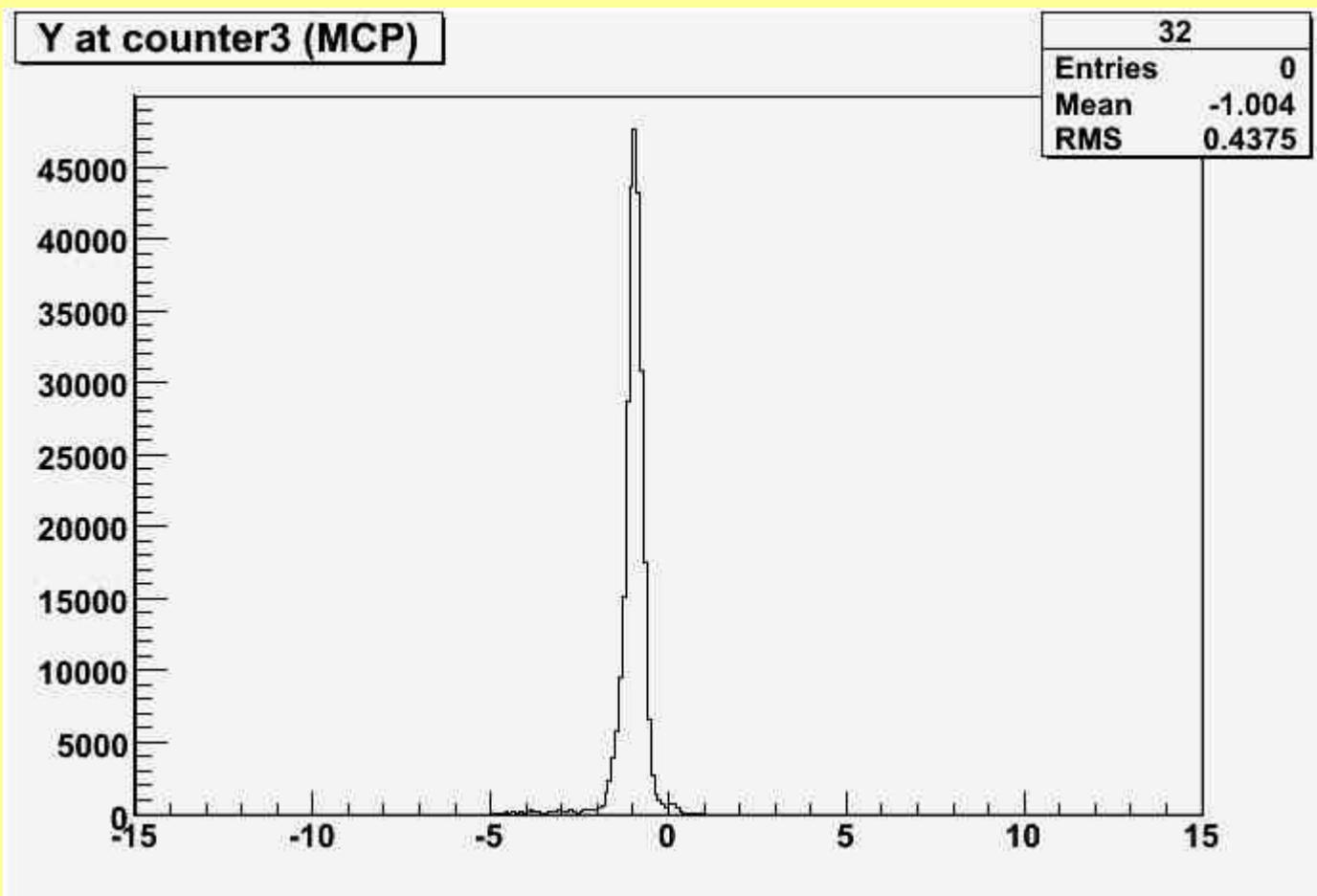
Positron incident angle at the sample



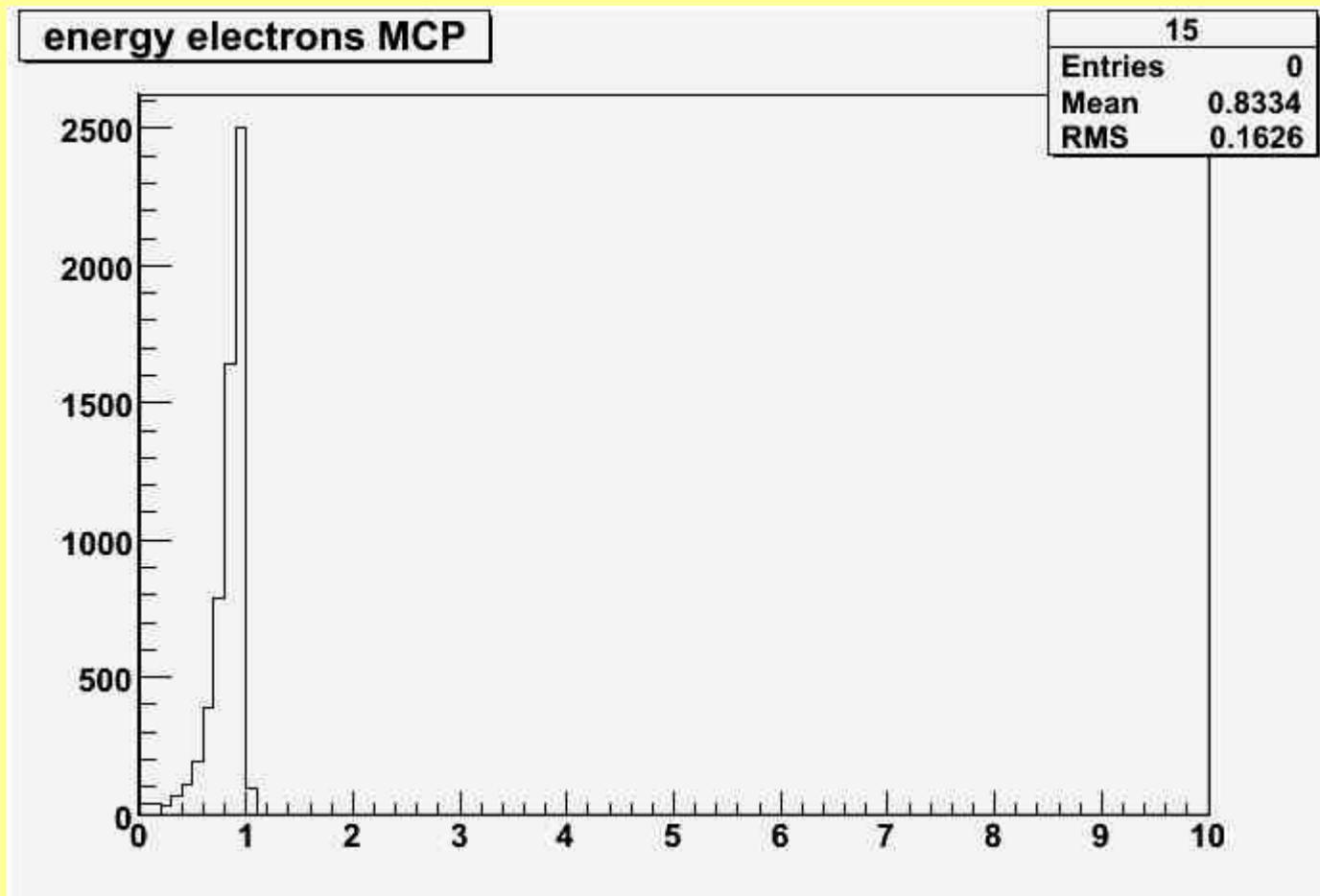
Energy of secondary emission electrons



Secondary electrons at MCP



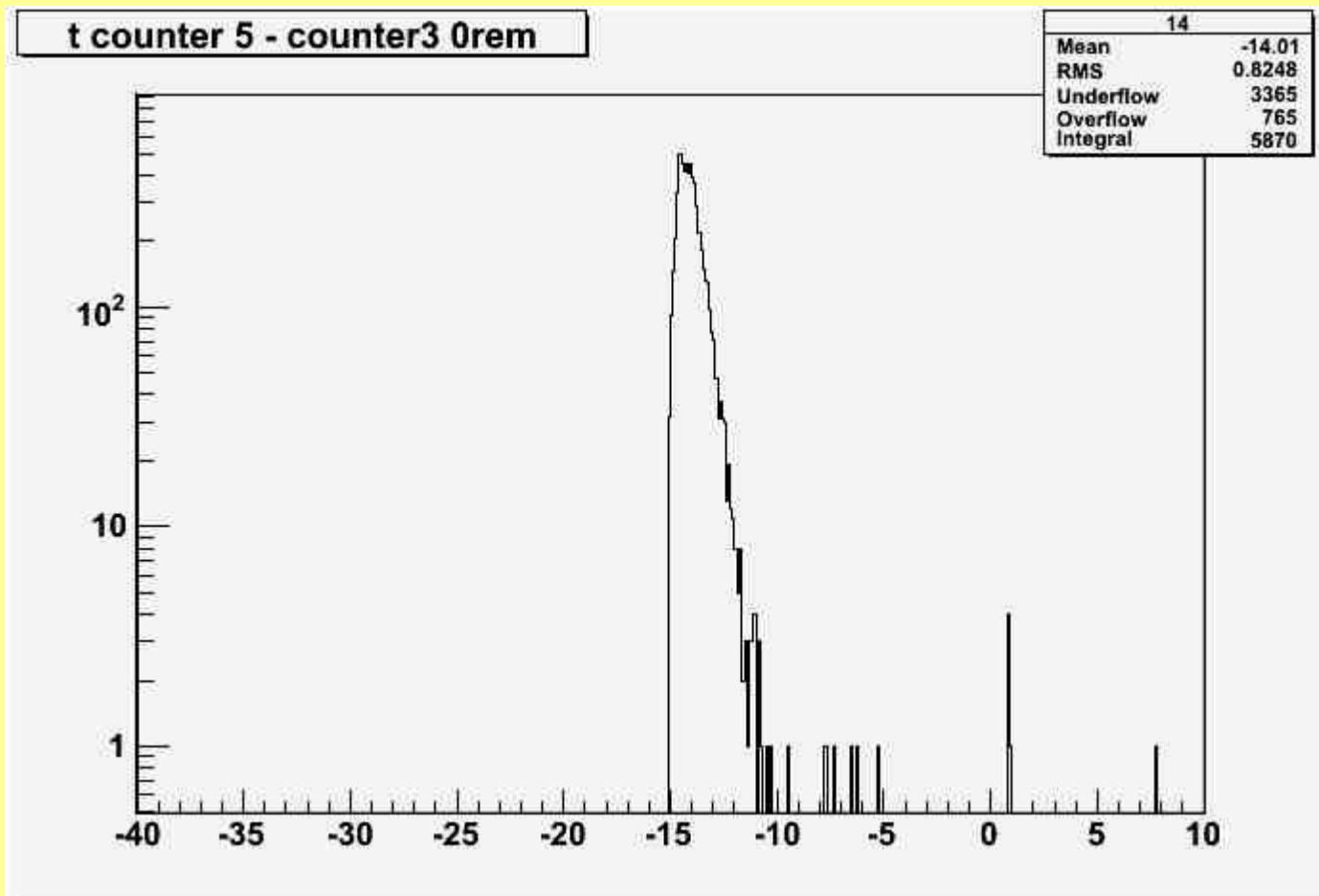
Secondary electrons at MCP: longitudinal energy of the first electron



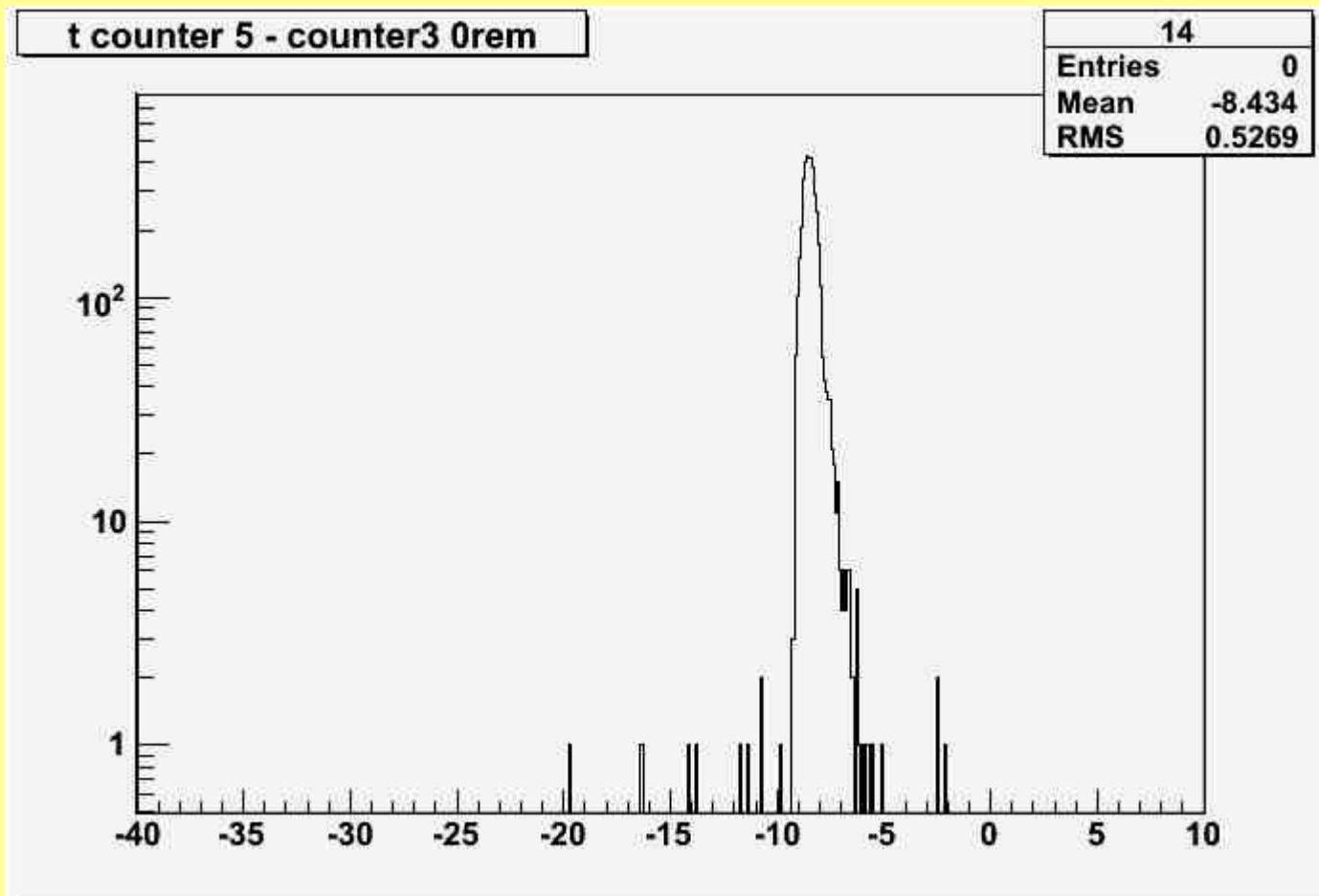
Systematics sources (tails)

- scattering of secondary electrons at the mesh
- backscattered positrons
- positron annihilation not at the sample

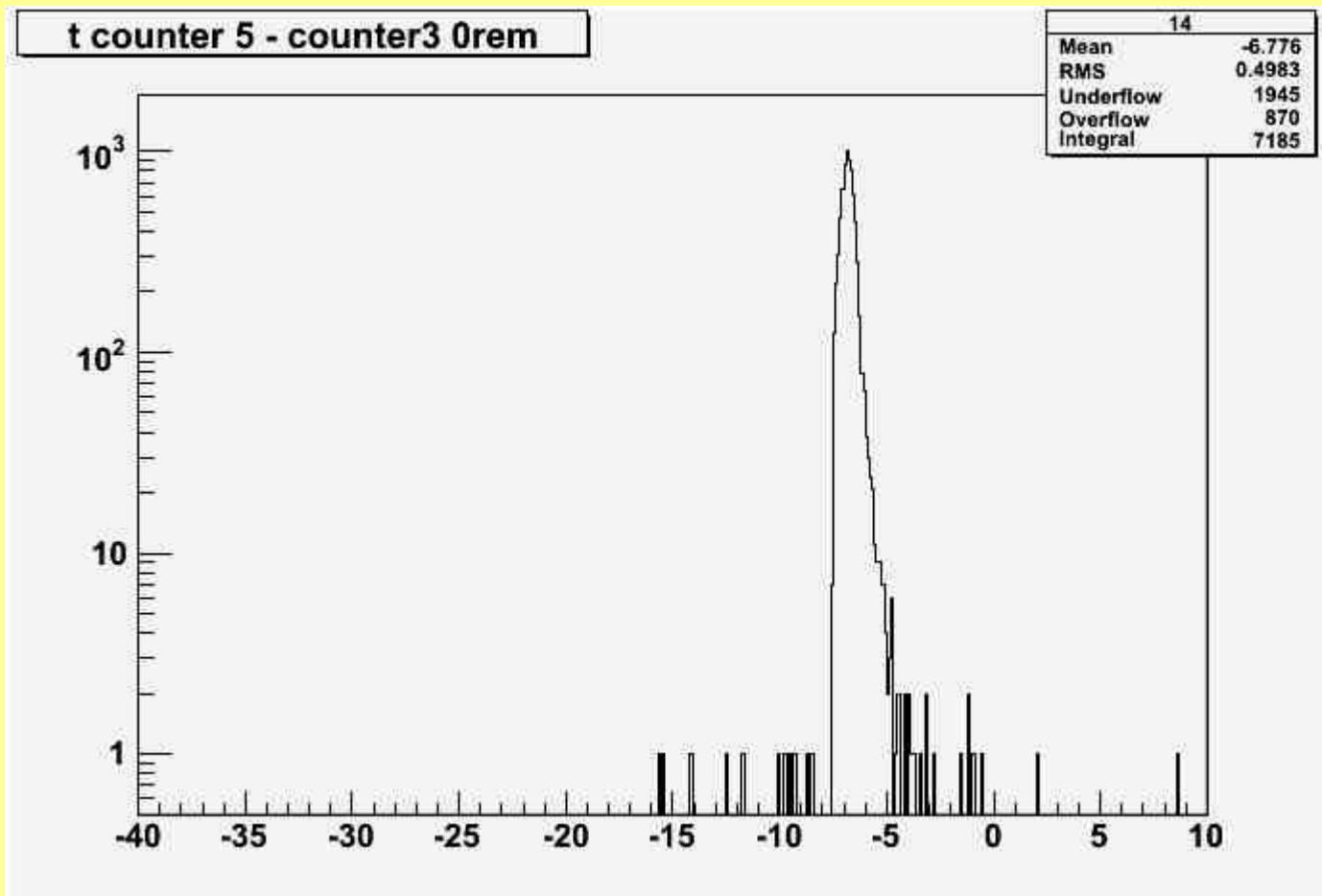
Time spectrum for 1000 V at the sample



Time spectrum for 3000 V at the sample



Time spectrum for 5000 V at the sample



Summary

We have designed and constructed
-high efficiency pulsed slow-positron beam, and
-secondary electron emission detector
for fundamental and applied researches.

SEED can be used for materials characterization.
There is still room for improvements

The simulation by GEANT4 preliminarily
describes the systematic effects in the setup